1090-49-79 **Matthew Badger*** (badger@math.sunysb.edu), Stony Brook University, Department of Mathematics, Stony Brook, NY 11794-3651. Extremal metrics for extremal length and modulus of measures.

For each $1 \le p < \infty$, we formulate a necessary and sufficient condition for an admissible metric to be extremal for the Fuglede *p*-modulus of a system of measures. When p = 2, this characterization generalizes Beurling's criterion, a sufficient condition for an admissible metric to be extremal for the extremal length of a planar curve family. (Received February 18, 2013)